

CFM - Conical Force Modulation mode

Conical Probe for Force Modulation Mode

Typical Tip Dimensions

Tip Radius	~ 8 nm (guaranteed < 10 nm)
Tip Style/Geometry	Conical
Tip Height	15 μm $\pm$ 2.5 μm
Tip Cone Angle	30 degrees

Typical Cantilever Properties

Spring Constant	3 N/m
Resonant Frequency	75 kHz
Length	225 μm
Width	42 μm
Thickness	3.0 μm

Aluminium coating on detector side of cantilever is available.

Please contact us about other coating options.

Common Properties

Material	single crystal silicon, n-type, highly doped
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Cantilevers per chip	one
Cantilever shape	Rectangular
Tip offset	~ 10 μm
Tip Aspect Ratio	1.5:1
Chip Dimensions	3.4 mm x 1.6 mm x 315 μm
Alignment Grooves	Yes

Typical Cantilever Specification

Spring Constant	3 N/m	Range: 1 - 7
Resonant Frequency	75 kHz	Range: 45 - 90
Length	225 μm	Range: 215 - 235
Width	42 μm	Range: 40 - 45
Thickness	3 μm	Range: 2 - 4

Team Nanotec guarantees 80 % of it's Aspire-Probes meet the specifications.

ReflexCoating:	Al-reflex,None
Quantity:	Qty 10,Qty 25,Qty 100,Qty 250,Qty 400